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**RESPONSE UNDER 37 CFR 1.116**  
**EXPEDITED PROCEDURES EXAMINING**  
**GROUP**

PATENT  
1630-0455PUS1

**IN THE U.S. PATENT AND TRADEMARK OFFICE**

Applicant: Jong Hyeok LEE Conf. No.: 9550  
Appl. No.: 10/769,813 Group: 2627  
Filed: February 3, 2004 Examiner: T. X. Dinh  
For: APPARATUS AND METHOD FOR DETERMINING TYPE OF  
OPTICAL DISK

**REPLY UNDER 37 C.F.R. § 1.116**

O.K.  
T.D.  
2/14/08  
**MS AF AMENDMENT**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In response to the Examiner's Office Action dated September 18, 2007, the following remarks are respectfully submitted in connection with the above-identified application.